

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Number : 10/553,470 Confirmation No.: 8935  
: National Phase of International App'l. No. PCT/DE2004/000801  
Applicant Ralf LERNER  
Filed : May 19, 2006  
Title : MONITORING THE REDUCTION OF THICKNESS AS  
MATERIAL IS REMOVED FROM A WAFER COMPOSITE AND  
TEST STRUCTURE FOR MONITORING REMOVAL OF  
MATERIAL  
TC/Art Unit : 2818  
Examiner: : Lopez Esquerro, Andres  
Docket No. : 60291.000041  
Customer No. : 21967

**Mail Stop: AF**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**NOTICE OF APPEAL**

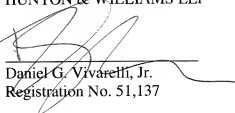
Sir:

Applicant hereby appeals to the Board of Patent Appeals and Interferences from the last decision of the Examiner rejecting claims 1-24 in the above-captioned application.

Please charge the undersigned's Deposit Account No. 50-0206 in the amount of \$540.00 to cover the Notice of Appeal fee. In the event of any variance between the amount enclosed and the fees determined by the U.S. Patent and Trademark Office, please charge or credit any such variance to the undersigned's Deposit Account No. 50-0206.

Respectfully submitted,  
HUNTON & WILLIAMS LLP

Dated: March 17, 2009

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